

A new testability calculation method to guide RTL test generation

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New method of testability calculation to guide RT-level test generation

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Testability analysis for efficient register-transfer level test generation [Electronic resource]

Nõmmeots, Tanel; Raik, Jaan; Ubar, Raimund-Johannes 9th International Conference MIXDES 2002 : Mixed Design of Integrated Circuits and Systems, Wroclaw, Poland, 20-22 June 2002 2002 / [4] p. [CD-ROM]

Testability guided hierarchical test generation with decision diagrams

Ubar, Raimund-Johannes; Raik, Jaan; Nõmmeots, Tanel 20th IEEE NORCHIP Conference : Copenhagen, Denmark, November 11-12, 2002 2002 / p. 265-271